

# Nonlinear Optics on the Silicon Platform

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**Abstract:** Silicon represents a mature, affordable platform for fabricating electronic and optical signal processing devices. We discuss all-optical 170 Gbit/s switching, a 42 Gbit/s electro-optic modulator, and proof-of-concept results for a surface plasmon polariton absorption modulator.

**OCIS codes:** (190.0190) Nonlinear optics, (130.0130) Integrated optics, (130.4815) Optical switching devices, 130.7405 Wavelength conversion devices, (130.4110) Modulators, 250.5403 Plasmonics

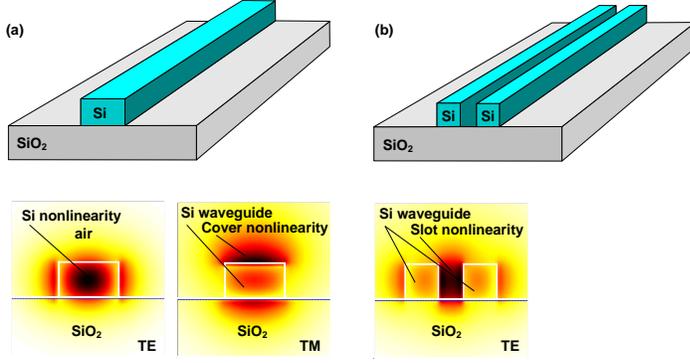
## 1. Introduction

Nonlinear effects in silicon support a large assortment of techniques for processing optical signals near wavelengths of 1.55 $\mu$ m at very high speed [1]. Especially the silicon-on-insulator (SOI) platform — typically a 220 nm thin silicon slab on top of a thick silicon oxide layer residing on a silicon substrate — allows strong field confinement in high index-contrast waveguides, thereby enhancing the native  $\chi^{(3)}$ -nonlinear response of silicon. The technology lends itself also to co-integrate electronic CMOS components [2], and to hybridly integrate active III-V [3] or Si/Ge devices [4]. The use of silicon nanocrystals [5] or amorphous silicon [6], and the addition of organic materials [7,8,9] (silicon-organic hybrid, SOH), of graphene [10,11], or of metallic structures [12,13] widens the scope even more by providing what silicon misses: A TPA-free  $\chi^{(3)}$  and a  $\chi^{(2)}$ -nonlinearity. In the following, we choose from the diverse applications of silicon-based devices [14] three important examples that exploit nonlinear effects on the silicon platform: An all-optical switch, a high-speed electro-optic modulator, and a plasmonic absorption modulator.

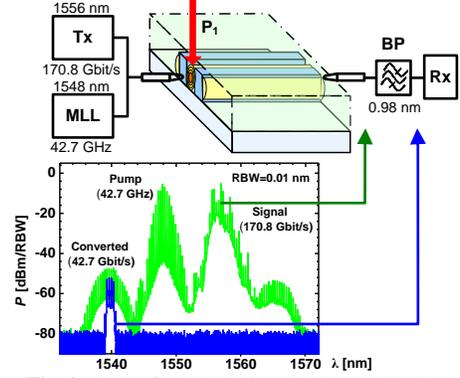
## 2. All-optical switching with FWM and XPM in $\chi^{(3)}$ -nonlinear strip and SOH slot waveguides

The SOI waveguides under consideration are depicted in Fig. 1a,b. The large  $\chi^{(3)}$ -nonlinearity of silicon cannot be fully exploited for fast all-optical switching due to the long lifetime and the loss of free carriers generated by two-photon absorption (TPA) [7,8]. To avoid these limitations experienced with a strip waveguide covered with air only, Fig. 1a(field lower left), we employ a highly nonlinear organic material [7,15] that does not suffer from TPA and has a low refractive index. Such SOH systems combine the strengths of both materials resulting in extremely large effective nonlinearities [7,9,15,8]. The SOH waveguides are silicon strips or vertical-slot SOI-structures (Fig. 1a,b) with a cladding of  $\chi^{(3)}$ -nonlinear organic material (DDMEBT [15]). The resulting SOH waveguide is described by a complex nonlinearity (NL) parameter  $\gamma$ . For maximum NL we need to optimize  $\text{Re}\{\gamma\} = n_2 k_0 / A_{\text{eff}}^{(3)}$  (effective area  $A_{\text{eff}}^{(3)}$ , vacuum wave number  $k_0$ , nonlinear-index coefficient  $n_2$ ). Optimized horizontal-slot quasi-TM waveguides were published recently [16]. TPA is quantified by a figure of merit  $\text{FOM}_{\text{TPA}} = -\text{Re}\{\gamma\} / (4\pi \text{Im}\{\gamma\}) (= n_2 / (\alpha_2 \lambda))$  with spatially homogeneous cross-section, TPA coefficient  $\alpha_2$ ). For the structures in Fig. 1a,b we measured [8]: Linear loss  $\alpha_{0 \text{ strip}} = 1 \text{ dB / mm}$ ,  $\alpha_{0 \text{ slot}} = 1.5 \text{ dB / mm}$ ;  $\text{FOM}_{\text{TPA core}} = 0.38$ ,  $\text{FOM}_{\text{TPA clad}} = 1.2$ ,  $\text{FOM}_{\text{TPA slot}} = 2.2$ ;  $\text{Re}\{\gamma\}_{\text{NL in core}} = 307/(\text{Wm})$ ,  $\text{Re}\{\gamma\}_{\text{NL in clad}} = 108/(\text{Wm})$ ,  $\text{Re}\{\gamma\}_{\text{NL in slot}} = 100/(\text{Wm})$ . For  $\text{FOM}_{\text{TPA}} > 0.5$ , TPA can be neglected.

We demonstrated the high-speed capability of nonlinear SOH slot waveguides with a number of experiments. Four-wave mixing (FWM) as in Fig. 2 demultiplexed a 170.8 Gbit/s OTDM signal to its four 42.7 Gbit/s tributaries [15]. The same setup is used for wavelength conversion with retiming. By FWM, a 42.7 Gbit/s RZ-OOK data signal at 1559 nm and a 42.7 GHz clock at 1550 nm generate a converted signal at 1541 nm with a quality factor of  $Q^2 = 11.3 \text{ dB}$  and on-chip powers for data (clock) of  $P_1 = 11.3 \text{ dBm}$  (21 dBm). We performed a similar experiment with NRZ DPSK data at 56 Gbit/s using an SOH strip waveguide as in Fig. 1a(field plot lower right). Finally, we demonstrated the transfer of 42.7 Gbit/s 33 % RZ-OOK PRBS data at 1541 nm to a CW carrier at 1544.5 nm via cross-phase modulation (XPM). In all cases, no bit pattern dependence was to be seen.



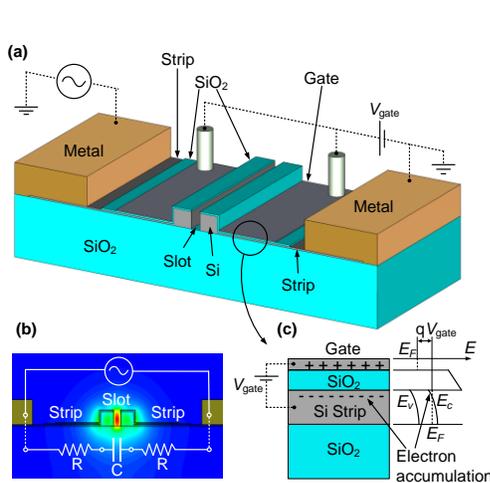
**Fig. 1.** Silicon waveguides (height 220 nm) with air or organic cover and electric field magnitudes [8]. (a) Si strip, width 360...400 nm, quasi-TE mode, SiO<sub>2</sub>/air cladding, Si core nonlinearity (lower left), and quasi-TM mode, strong cover nonlinearity (lower right). (b) Quasi-TE Si slot waveguide, rail widths 220 nm, slot width 160...200 nm, cladding/slot nonlinearity



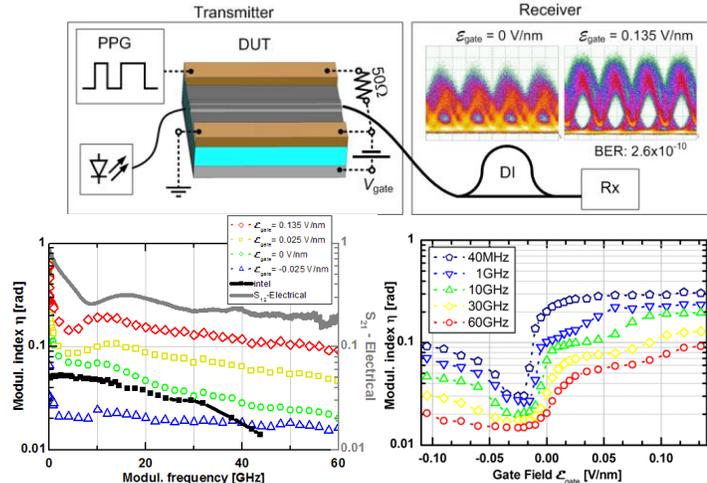
**Fig. 2.** Setup for FWM demultiplexer with 4 mm long SOH slot waveguide, Fig. 1b. Output spectrum before and after bandpass filter BP [15]. Tx: transmitter; Rx: receiver; MLL: mode-locked laser

### 3. Electro-optic modulator with $\chi^{(2)}$ -nonlinear SOH slot waveguide

The CMOS-compatible SOH approach for optical modulators exploits the properties of a  $\chi^{(2)}$ -nonlinear organic material which covers a slot waveguide, Fig. 1b and Fig. 3a. A metallic travelling-wave transmission line connects the modulator voltage to the electro-optic active slot region. It must be both optically transparent and electrically highly conductive, so we induce a highly conductive electron accumulation layer by an external DC “gate” voltage  $V_{\text{gate}}$ . As opposed to doping, the electron mobility in this case is not impaired by impurity scattering. Using a first-generation device at a data rate of 42.7 Gbit/s, widely open eye diagrams were recorded [17], Fig. 4. The measured frequency response suggests that significantly larger data rates are feasible. Compared to a recently published similarly fast  $pn$ -junction modulator [18], our device is more broadband ( $> 60$  nm) and more sensitive ( $V_{\pi} = 9$  Vmm @ 1 kHz).



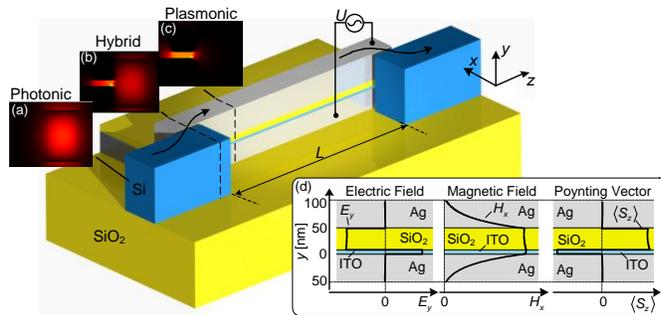
**Fig. 3.** SOH modulator, rail (slot) widths 240 nm (120 nm), length 1.7 mm, slot filled with organic material [17] (M1, chromophores dispersed in amorphous polycarbonate, APC). Electro-optic coefficient with optimum *in situ* poling  $r_{33} = 70$  pm/V. (a) Silicon strips connect optical region with metal electrodes. A positive gate voltage  $V_{\text{gate}}$  bends the bands ( $E_{C,V,F}$ : conduction, valence band, and Fermi energy;  $q$ : elementary charge) resulting in a highly conductive electron accumulation layer. (b) Waveguide cross-section and electric optical field magnitude with equivalent circuit ( $C$ : slot capacitance;  $R$ : strip resistance). [Reprint from [17] © 2011 OSA]



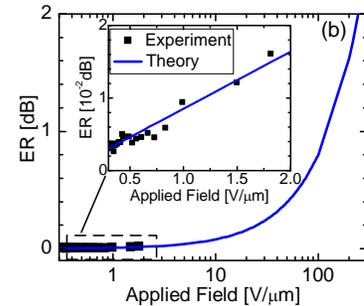
**Fig. 4.** SOH modulator (simplified realization compared to Fig.3a) and experimental results. (upper row) Setup with 42.7 Gbit/s pulse pattern generator (PPG) and delay interferometer (DI) for phase-to-amplitude conversion. (lower row) Phase modulation index  $\eta$  for various gate electric field strengths  $\mathcal{E}_{\text{gate}}$  and sinusoidal modulation voltages with 1 V amplitude and frequencies  $f_{\text{mod}} = 1$  kHz...60 GHz. For large  $|\mathcal{E}_{\text{gate}}|$  the SI strips become more conductive due to an electron accumulation (hole inversion) layer for  $\mathcal{E}_{\text{gate}} > 0.025$  V/nm ( $\mathcal{E}_{\text{gate}} < -0.025$  V/nm). Transmission of electrical waveguide (voltage ratio  $|S_{21}|$ , —). For  $\mathcal{E}_{\text{gate}} = 0.135$  V/nm and  $f_{\text{mod}} = 1$  kHz (60 GHz) we found  $V_{\pi}L = 9$  Vmm (58 Vmm) corresponding to  $V_{\pi} = 5.3$  V (34 V). Flat response for  $f_{\text{mod}} > 2$  GHz, suggesting that data rates could be extended well beyond the 42.7 Gbit/s limit of our equipment. [Reprinted from [17] © 2011 OSA]

### 4. Surface plasmon polariton absorption modulator

To reduce the modulator footprint even further, an electrically controlled ultra-compact surface plasmon polariton (SPP) absorption modulator (SPPAM) was investigated. The device can be as short as 10  $\mu\text{m}$ , depending on the re-



**Fig. 5** Surface plasmon polariton (SPP) absorption modulator (SPPAM). With a directional coupler, light is coupled from a silicon nanowire into an active plasmonic section, consisting of stacked layers of silver (Ag), indium tin oxide (ITO, 10 nm), and SiO<sub>2</sub>. The SPP absorption coefficient is modulated by a voltage  $U$  between the silver electrodes. *Insets:* The photonic mode (a) in the silicon nanowire excites via a hybrid mode (b) in the directional coupler an SPP (c). Inset (d) shows the electric field  $E_y$ , the magnetic field  $H_x$ , and the time-averaged Poynting vector ( $S_z$ ) in the active plasmonic region, demonstrating the strong SPP confinement in the ITO layer. The modulator length is  $L = 10 \mu\text{m}$ . [Reprint from [19] © 2011 OSA]



**Fig. 6.** Measured (■) and predicted (—) extinction ratio (ER) at kHz-frequencies as a function of the applied modulation field. An ER of 1 dB is obtained with an electric field of  $100 \text{ V} / \mu\text{m}$ . Such a field strength can be easily achieved in the structure Fig. 5, and is far below the dielectric strength in the order of  $10^3 \text{ V} / \mu\text{m}$  for materials like SiO<sub>2</sub> and Si<sub>3</sub>N<sub>4</sub>. [Reprint from [19] © 2011 OSA]

quired extinction ratio (ER) and the acceptable loss. The absorption modulator Fig. 5 comprises a stack of metal / insulator / metal-oxide / metal layers, which supports a strongly confined SPP in the  $1.55 \mu\text{m}$  wavelength region. The absorption is modulated by electrically changing the free carrier density in the intermediate metal-oxide layer. A three-layer prototype was designed, and the concept is supported by proof-of-principle experiments, Fig. 6.

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